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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	564
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	4000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1440a-vq100i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Product Plan

		Speed	Grade ¹			Applic	cation ¹	
Device/Package	Std.	-1	-2	-3	С	I	М	В
A1415A Device		1		1			•	
84-Pin Plastic Leaded Chip Carrier (PLCC)	1	1	D	D	✓	1	1	-
100-Pin Plastic Quad Flatpack (PQFP)	1	✓	D	D	✓	1	1	-
100-Pin Very Thin Quad Flatpack (VQFP)	1	1	D	D	1	1	1	-
100-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	-	-	-
A14V15A Device							•	
84-Pin Plastic Leaded Chip Carrier (PLCC)	1	-	-	—	✓	-	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	1	-	-	-	1	-	-	-
A1425A Device	1	I		1			1	
84-Pin Plastic Leaded Chip Carrier (PLCC)	1	✓	D	D	✓	1		
100-Pin Plastic Quad Flatpack (PQFP)	1	1	D	D	1	✓	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	1	1	D	D	1	1	-	-
132-Pin Ceramic Quad Flatpack (CQFP)	1	1	-	-	1	-	1	1
133-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	_	D	D
160-Pin Plastic Quad Flatpack (PQFP)	1	✓	D	D	✓	~	-	-
A14V25A Device	•		•			•		
84-Pin Plastic Leaded Chip Carrier (PLCC)	1	-	-	—	✓	-	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	1	-	-	-	1	-	-	-
160-Pin Plastic Quad Flatpack (PQFP)	1	-	-	-	1	-	-	-
A1440A Device		1	L	1	J		1	
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	1	D	D	1	1	_	-
100-Pin Very Thin Quad Flatpack (VQFP)	1	1	D	D	✓	✓	-	-
160-Pin Plastic Quad Flatpack (PQFP)	 ✓ 	1	D	D	1	1	-	-
175-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	-	-	-
176-Pin Thin Quad Flatpack (TQFP)	1	1	D	D	1	1	-	_

Notes:

 Applications:
 C = Commercial
 I = Industrial M = Military

Availability: $\checkmark = Available$ P = Planned

- = Not plannedD = Discontinued

Speed Grade: -1 = Approx. 15% faster than Std. -2 = Approx. 25% faster than Std. -3 = Approx. 35% faster than Std. (-2 and -3 speed grades have been discontinued.)

Microsemi

Accelerator Series FPGAs – ACT 3 Family

		Speed	Grade ¹		Application ¹				
Device/Package	Std.	-1	-2	-3	С	I	м	В	
A14V40A Device		1	1			1	•		
84-Pin Plastic Leaded Chip Carrier (PLCC)	1	-	-	-	✓	-	-	-	
100-Pin Very Thin Quad Flatpack (VQFP)	1	_	_	-	1	_	-	-	
160-Pin Plastic Quad Flatpack (PQFP)	1	_	_	-	1	_	-	-	
176-Pin Thin Quad Flatpack (TQFP)	1	_	-	-	1	-	-	-	
A1460A Device		1	1						
160-Pin Plastic Quad Flatpack (PQFP)	1	 ✓ 	D	D	 ✓ 	1	-	-	
176-Pin Thin Quad Flatpack (TQFP)	1	1	D	D	1	1	-	-	
196-Pin Ceramic Quad Flatpack (CQFP)	1	1	_	-	1	_	1	1	
207-Pin Ceramic Pin Grid Array (CPGA)	1	1	D	D	1	-	1	1	
208-Pin Plastic Quad Flatpack (PQFP)	1	✓	D	D	~	✓	-	-	
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	-	-	-	
A14V60A Device		1	1			1	•		
160-Pin Plastic Quad Flatpack (PQFP)	✓	-	-	-	✓	_	-	-	
176-Pin Thin Quad Flatpack (TQFP)	1	-	-	-	✓	_	-	-	
208-Pin Plastic Quad Flatpack (PQFP)	1	-	-	-	✓	-	-	-	
A14100A Device				•	•				
208-Pin Power Quad Flatpack (RQFP)	1	✓	D	D	✓	✓	-	-	
257-Pin Ceramic Pin Grid Array (CPGA)	1	1	D	D	 ✓ 	_	1	1	
313-Pin Plastic Ball Grid Array (BGA)	1	✓	D	D	✓	_	-	-	
256-Pin Ceramic Quad Flatpack (CQFP)	1	1	-	-	1	_	~	1	
A14V100A Device	•	•	•	•	•	•	-		
208-Pin Power Quad Flatpack (RQFP)	1	-	-	-	✓	_	-	-	
313-Pin Plastic Ball Grid Array (BGA)	1	_	-	-	1	-	-	-	

Notes:

1. Applications: C = CommercialI = Industrial
M = Military
Commercial only

- Availability:
- ✓ = Available
- P = Planned- = Not planned
- D = Discontinued

Speed Grade:

-1 = Approx. 15% faster than Std. -2 = Approx. 25% faster than Std. -3 = Approx. 35% faster than Std. (-2 and -3 speed grades have been discontinued.)

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.

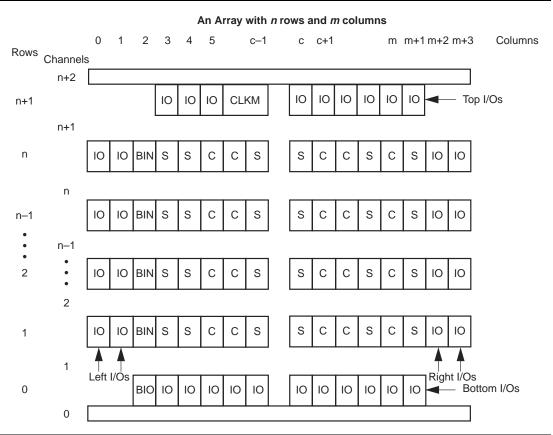


Figure 2-1 • Generalized Floor Plan of ACT 3 Device



A1460A, A14V60A Timing Characteristics

Table 2-30 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic N	Iodule Propagation Delays ²	-3 S	peed ³	-2 Sp	beed ³	-1 S	peed	Std. S	Speed	3.3 V Speed ¹		Units
Parame	eter/Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predict	ed Routing Delays ⁴											
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic N	Nodule Sequential Timing											
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.

4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.



A1460A, A14V60A Timing Characteristics (continued)

Table 2-32 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Mod	dule – TTL Output Timing ¹	-3 Sp	beed ²	-2 Sp	beed ²	–1 S	peed	Std.	Speed	3.3 V	Speed ¹	Units
Parame	eter/Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.8		8.7		9.9		11.6		15.1	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.0		11.5		15.0	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Moo	dule – CMOS Output Timing ¹				•							
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.1		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. Delays based on 35 pF loading.

2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.



A14100A, A14V100A Timing Characteristics

Logic N	Iodule Propagation Delays ²	-3 S	peed ³	-2 Sp	beed ³	–1 S	peed	Std. S	Speed	3.3 V Speed ¹		Units
Parame	eter/Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predict	ed Routing Delays ⁴											
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic N	Nodule Sequential Timing											
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.

4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A14100A, A14V100A Timing Characteristics (continued)

Table 2-35 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Moo	dule Input Propagation Delays	-3 S	beed ¹	-2 S	beed ¹	–1 S	peed	Std.	Speed 3.3 V Speed ¹		Units	
Parame	eter/Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predict	ed Input Routing Delays ²											
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Moo	dule Sequential Timing (wrt IOCLK	pad)							1			
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	1.2		1.4		1.5		1.8		1.8		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		1.0		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		1.0		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.5		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		2.0		2.0		2.0		ns

Notes: *

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.

 Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.



A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Moo	dule – TTL Output Timing ¹	-3 SI	beed ²	–2 Sp	beed ²	–1 S	peed	Std.	Speed	3.3 V	Speed ¹	Units
Parame	eter/Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Moo	dule – CMOS Output Timing ¹				•		•					
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

1. Delays based on 35 pF loading.

2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.

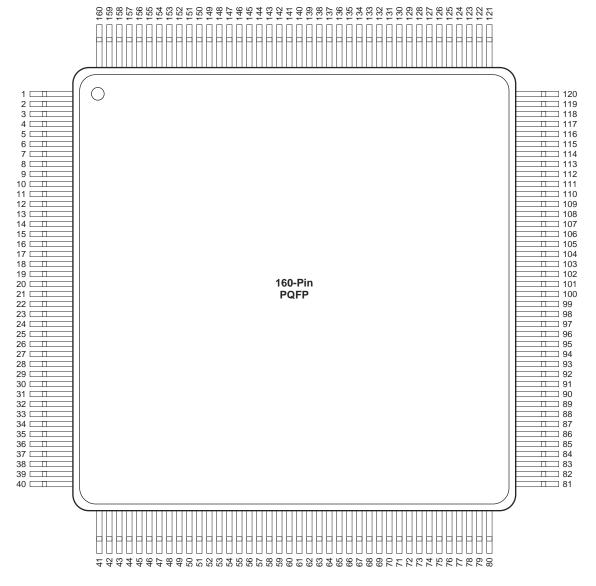


	PL84									
Pin Number	A1415, A14V15 Function	A1425, A14V25 Function	A1440, A14V40 Function							
1	VCC	VCC	VCC							
2	GND	GND	GND							
3	VCC	VCC	VCC							
4	PRA, I/O	PRA, I/O	PRA, I/O							
11	DCLK, I/O	DCLK, I/O	DCLK, I/O							
12	SDI, I/O	SDI, I/O	SDI, I/O							
16	MODE	MODE	MODE							
27	GND	GND	GND							
28	VCC	VCC	VCC							
40	PRB, I/O	PRB, I/O	PRB, I/O							
41	VCC	VCC	VCC							
42	GND	GND	GND							
43	VCC	VCC	VCC							
45	HCLK, I/O	HCLK, I/O	HCLK, I/O							
52	SDO	SDO	SDO							
53	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O							
59	VCC	VCC	VCC							
60	VCC	VCC	VCC							
61	GND	GND	GND							
68	VCC	VCC	VCC							
69	GND	GND	GND							
74	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O							
83	CLKA, I/O	CLKA, I/O	CLKA, I/O							
84	CLKB, I/O	CLKB, I/O	CLKB, I/O							

Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. NC denotes no connection.
- 3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ160



Note: This is the top view of the package

Note

Microsemi

Accelerator Series FPGAs – ACT 3 Family

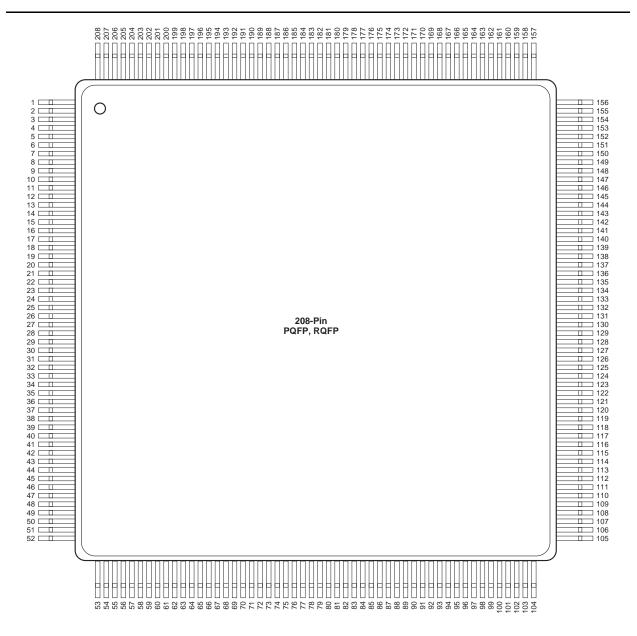
PQ160									
Pin Number	A1425, A14V25 Function	A1440, A14V40 Function	A1460, A14V60 Function						
92	NC	I/O	I/O						
93	NC	I/O	I/O						
98	GND	GND	GND						
99	VCC	VCC	VCC						
100	NC	I/O	I/O						
103	GND	GND	GND						
107	NC	I/O	I/O						
109	NC	I/O	I/O						
110	VCC	VCC	VCC						
111	GND	GND	GND						
112	VCC	VCC	VCC						
113	NC	I/O	I/O						
119	NC	I/O	I/O						
120	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O						
121	GND	GND	GND						
124	NC	I/O	I/O						
127	NC	I/O	I/O						
136	CLKA, I/O	CLKA, I/O	CLKA, I/O						
137	CLKB, I/O	CLKB, I/O	CLKB, I/O						
138	VCC	VCC	VCC						
139	GND	GND	GND						
140	VCC	VCC	VCC						
141	GND	GND	GND						
142	PRA, I/O	PRA, I/O	PRA, I/O						
143	NC	I/O	I/O						
145	NC	I/O	I/O						
147	NC	I/O	I/O						
149	NC	I/O	I/O						
151	NC	I/O	I/O						
153	NC	I/O	I/O						
154	VCC	VCC	VCC						
160	DCLK, I/O	DCLK, I/O	DCLK, I/O						

Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. NC denotes no connection.
- 3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.



PQ208, RQ208



Note: This is the top view of the package

Note

Accelerator Series FPGAs - ACT 3 Family

	PQ208, RQ20	8		PQ208, RQ20	8
Pin Number	A1460, A14V60 Function	A14100, A14V100 Function	Pin Number	A1460, A14V60 Function	A14100, A14V100 Function
1	GND	GND	115	VCC	VCC
2	SDI, I/O	SDI, I/O	116	NC	I/O
11	MODE	MODE	129	GND	GND
12	VCC	VCC	130	VCC	VCC
25	VCC	VCC	131	GND	GND
26	GND	GND	132	VCC	VCC
27	VCC	VCC	145	VCC	VCC
28	GND	GND	146	GND	GND
40	VCC	VCC	147	NC	I/O
41	VCC	VCC	148	VCC	VCC
52	GND	GND	156	IOCLK, I/O	IOCLK, I/O
53	NC	I/O	157	GND	GND
60	VCC	VCC	158	NC	I/O
65	NC	I/O	164	VCC	VCC
76	PRB, I/O	PRB, I/O	180	CLKA, I/O	CLKA, I/O
77	GND	GND	181	CLKB, I/O	CLKB, I/O
78	VCC	VCC	182	VCC	VCC
79	GND	GND	183	GND	GND
80	VCC	VCC	184	VCC	VCC
82	HCLK, I/O	HCLK, I/O	185	GND	GND
98	VCC	VCC	186	PRA, I/O	PRA, I/O
102	NC	I/O	195	NC	I/O
103	SDO	SDO	201	VCC	VCC
104	IOPCL, I/O	IOPCL, I/O	205	NC	I/O
105	GND	GND	208	DCLK, I/O	DCLK, I/O
114	VCC	VCC			•

Notes:

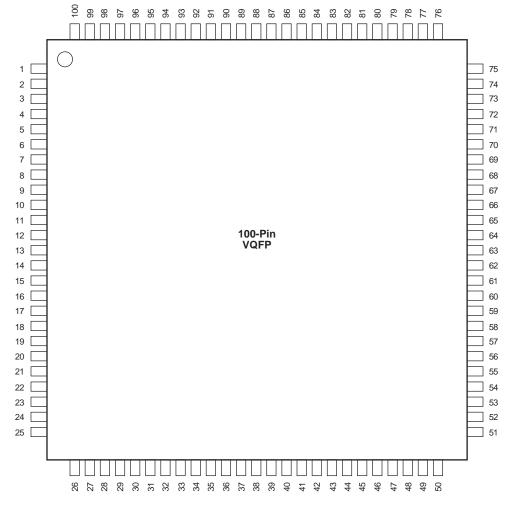
1. All unlisted pin numbers are user I/Os.

2. NC denotes no connection.

3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.



VQ100



Note: This is the top view.

Note

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Accelerator Series FPGAs - ACT 3 Family

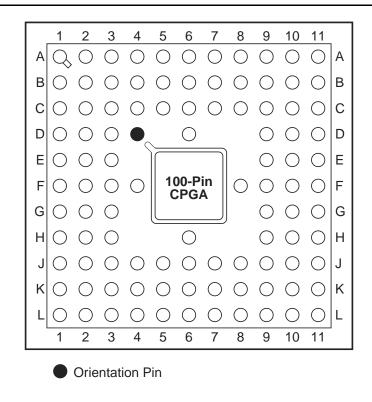
CQ196		CQ196	
Pin Number	A1460 Function	Pin Number	A1460 Function
1	GND	101	GND
2	SDI, I/O	110	VCC
11	MODE	111	VCC
12	VCC	112	GND
13	GND	137	VCC
37	GND	138	GND
38	VCC	139	GND
39	VCC	140	VCC
51	GND	148	IOCLK, I/O
52	GND	149	GND
59	VCC	155	VCC
64	GND	162	GND
77	HCLK, I/O	172	CLKA, I/O
79	PRB, I/O	173	CLKB, I/O
86	GND	174	PRA, I/O
94	VCC	183	GND
98	GND	189	VCC
99	SDO	193	GND
100	IOPCL, I/O	196	DCLK, I/O

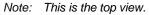
Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. NC denotes no connection.
- 3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.



PG100





Note

4 – Datasheet Information

List of Changes

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page
Revision 3 (January 2012)	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35820).	2-21
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35820).	
Revision 2 (September 2011)	The ACT 3 datasheet was formatted newly in the style used for current datasheets. The same information is present (other than noted in the list of changes for this revision) but divided into chapters.	N/A
	The datasheet was revised to note in multiple places that speed grades -2 and -3 have been discontinued. The following device/package combinations have been discontinued for all speed grades and temperatures (SAR 33872): A1415 PG100 A1425 PG133 A1440 PG175 A1460 BG225 Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004.	I and others
	The "Features" section was revised to state the clock-to-ouput time and on-chip performance for –1 speed grade as 9.0 ns and 186 MHz. The "General Description" section was revised in accordance (SAR 33872).	Ι
	The maximum performance values were updated in Table 1 • ACT 3 Family Product Information, and now reflect worst-case commercial for the -1 speed grade (SAR 33872).	Ι
	The "Product Plan" table was updated as follows to conform to current offerings (SAR 33872): The A1415A device is offered in PL84, PG100, and VQ100 packages for Military application. The A1440A device is offered in TQ176 and VQ100 packages for Industrial application.	111
	Table 1-1 • Chip-to-Chip Performance (worst-case commercial) was updated to include data for all speed grades instead of only –3 (SAR 33872).	1-2
	Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade) was revised to reflect values for the –1 speed grade (SAR 33872).	1-1
	Figure 2-10 • Timing Model was updated to show data for the –1 speed grade instead of –3 (SAR 33872).	2-16
	Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions was updated to include data for all speed grades instead of only –3 (SAR 33872).	2-20
	Package names used in the "Package Pin Assignments" section and throughout the document were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 27395).	3-1



Datasheet Information

Revision	Changes	
Revision 2 (continued)	In the "Package Pin Assignments" section, notes were added to the pin tables for the following packages, stating that they are discontinued:	
	"BG225"	3-20
	"PG100"	3-24
	"PG133"	3-26
	"PG175"	3-28
Revision 1 (June 2006)	RoHS compliant information was added to the "Ordering Information" section.	